

# Product / Process Change Notification



N° 2014-014-A

Dear Customer,

Please find attached our INFINEON Technologies PCN:

## ISO1H801G – Design Change

Important information for your attention:

- Please respond to this PCN by indicating your decision on the approval form, sign it and return to your sales partner before 30. June 2014.
- Infineon aligns with the widely-recognized JEDEC STANDARD "JESD46", which stipulates: "Lack of acknowledgement of the PCN within 30 days constitutes acceptance of the change."

Your prompt reply will help Infineon Technologies to assure a smooth and well executed transition. If Infineon does not hear from your side by the due date, we will assume your full acceptance to this proposed change and its implementation.

Your attention and response to this matter is greatly appreciated.

Disclaimer:

If we do not receive any response within the given time limit we consider this as the acceptance of the PCN.

# Product / Process Change Notification



N° 2014-014-A

**SUBJECT OF CHANGE:** Modification of the communication protocol across the galvanic isolation.

<b>PRODUCTS AFFECTED:</b>	<b>Sales Name</b>	<b>SP No.</b>	<b>OPN</b>	<b>Package</b>
	ISO1H801G	SP000722122	ISO1H801GAUMA1	PG-DSO-36

**REASON OF CHANGE:** Improve the capability to meet customer's volume demand.

<b>DESCRIPTION OF CHANGE:</b>	<u><b>OLD</b></u>	<u><b>NEW</b></u>
■	Transceiver with differential method for binary data transfer	Transceiver with separated transfer of binary values on two independent channels

**PRODUCT IDENTIFICATION:** Traceability is ensured by datecode.

## TIME SCHEDULE:

■ Final qualification report:	October 2014
■ First samples available:	July 2014
■ Start of delivery:	From January 2015 onwards

**ASSESSMENT:** No change in form, fit and function.

**DOCUMENTATION:** 2\_cip14014\_qualification plan

**PCN 2014-014-A  
ISO1H801G – Design Change**



**Final Qualification Report**

**Date: 2014-11-18**

Reason for choosing following test vehicle: Device itself  
 Extension of qualification:  
 Assessment of Q-Results Pass

Reference Products				ISO1H801G
Test description	Abbr.	Condition	Readout	
<b>Pre-Conditioning</b> J-STD-20-D JEESD22 A111	<b>PC</b>			MSL3, 245°C, 3x reflow
<b>Temperature Cycling</b> JESD22 A104	<b>TC*</b>	Ta min = -55 °C Ta max = +150 °C	0 cyc precon 500 cyc 1000 cyc	0 / 77 0 / 77 0 / 77 0 / 77
<b>Autoclave</b> JESD22 A102	<b>AC*</b>	Ta = 121°C RH = 100%	0 h precon 96 h	0 / 77 0 / 77 0 / 77
<b>Temperature Humidity Bias</b> JESD22 A101	<b>THB*</b>	T = 85 °C RH = 85%	0 h precon 168 h 500 h 1000 h	0 / 77 0 / 77 0 / 77 0 / 77 0 / 77
<b>High Temperature Storage Life</b> JESD22 A-103	<b>HTSL</b>	Ta =150°C	0 h precon 168 h 500 h 1000 h	0 / 77 - 0 / 77 0 / 77 0 / 77
<b>High Temperature Operating Life</b> JESD22 A108	<b>HTOL</b>	Tj = 150 °C	0 h precon 168 h 500 h 1000 h	0 / 77 - 0 / 77 0 / 77 0 / 77
<b>ESD Characterization HBM</b> JEDEC22 A114	<b>ESD</b>	HBM		HBM/2 Withstand Voltage 2500V
<b>ESD Characterization CDM</b> JEDEC22 C101	<b>ESD</b>	CDM		CDM/Class3 Withstanf Voltage 1500V
<b>Latch-Up</b> JESD78	<b>LU</b>			Pass
<b>Electrical Distribution</b>	<b>ED</b>	-40 °C +25 °C +125 °C		0 / 30 0 / 30 0 / 30

\* PC is done only for SMD Packages before AC, TC, THB, HAST stress tests

Abbreviations - not performed